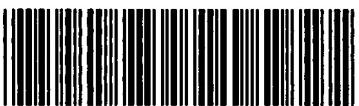


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10717607	KIM ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Keefer, Michael E	2154

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	227	7/13/2007	MEK

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Search	7/13/2007	MEK
Consulted Examiner Hassan Phillips	7/12/2007	MEK
Consulted Examiner Dustin Nguyen	7/12/2007	MEK

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>